

Form 1449 (Modified) Information Disclosure Statement By Applicant (Use Several Sheets if Necessary)	Atty Docket No.	Application No.:
	KLA1P107	Unassigned
	Applicant:	16/796,577
	Testoni	
	Filing Date	Group
	Herewith 3/8/04	Unassigned 2881

U.S. Patent Documents

Examiner Initial	No.	Patent No.	Date	Patentee	Class	Sub-class	Filing Date
AQ	A	6,407,386	06/18/02	Dotan et al.			
	B						
	C						
	D						
	E						
	F						
	G						
	H						
	I						

Foreign Patent or Published Foreign Patent Application

Examiner Initial	No.	Document No.	Publication Date	Country or Patent Office	Class	Sub-class	Translation	
							Yes	No
	J							
	K							
	L							
	M							
	N							

Other Documents

Examiner Initial	No.	Author, Title, Date, Place (e.g. Journal) of Publication
AQ	O	Serulnik, "Defect Topographic Maps Using a Non-Lambertian Photometric Stereo Method", Applied Materials, Israel Ltd., July 2002
	P	
	Q	
Examiner /Anthony Quash/		Date Considered 05/15/2006

Examiner: Initial citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.